

TC7MH175FK

Quad D-Type Flip-Flop with Clear

The TC7MH175FK is an advanced high speed CMOS quad D-type flip-flop fabricated with silicon gate C²MOS technology.

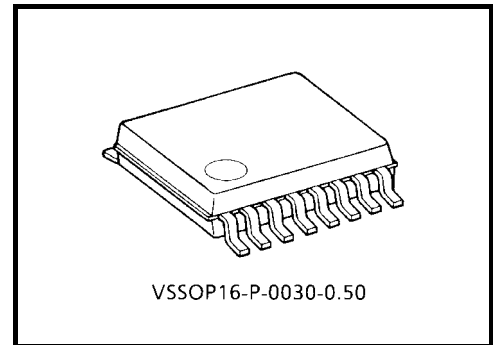
It achieves the high speed operation similar to equivalent bipolar schottky TTL while maintaining the CMOS low power dissipation.

These four flip-flops are controlled by a clock input (CK) and a clear input ($\overline{\text{CLR}}$).

The information data applied to the D inputs (D1 thru D4) are transferred to the outputs (Q1 thru Q4 and $\overline{\text{Q}}$ 1 thru $\overline{\text{Q}}$ 4) on the positive-going edge of the clock pulse.

When the $\overline{\text{CLR}}$ input is held low, the Q outputs are at the low logic level and the $\overline{\text{Q}}$ outputs are at the high logic level, regardless of other input conditions.

An input protection circuit ensures that 0 to 5.5 V can be applied to the input pins without regard to the supply voltage. This device can be used to interface 5 V to 3 V systems and two supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

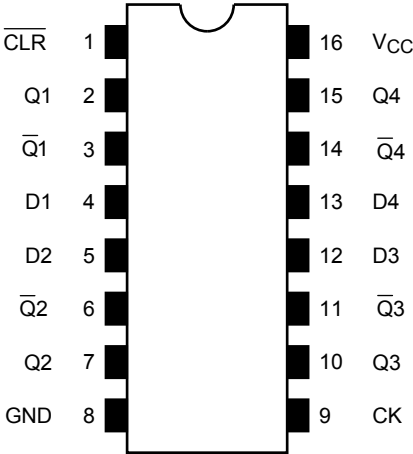


Weight: 0.02 g (typ.)

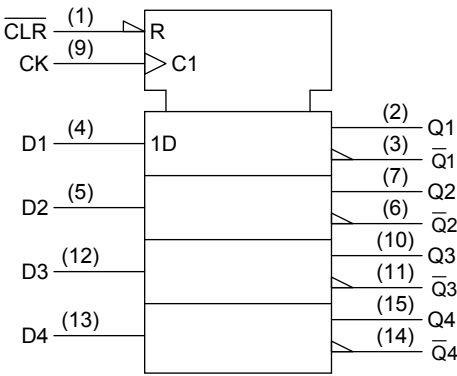
Features

- High speed: $f_{\text{max}} = 210 \text{ MHz}$ (typ.) ($V_{\text{CC}} = 5 \text{ V}$)
- Low power dissipation: $I_{\text{CC}} = 4 \mu\text{A}$ (max) ($T_a = 25^\circ\text{C}$)
- High noise immunity: $V_{\text{NIH}} = V_{\text{NIL}} = 28\% V_{\text{CC}}$ (min)
- Power down protection is provided on all inputs.
- Balanced propagation delays: $t_{\text{pLH}} \approx t_{\text{pHL}}$
- Wide operating voltage range: $V_{\text{CC (opr)}} = 2 \sim 5.5 \text{ V}$
- Low noise: $V_{\text{OLP}} = 0.8 \text{ V}$ (max)
- Pin and function compatible with 74ALS175

Pin Assignment (top view)



IEC Logic Symbol

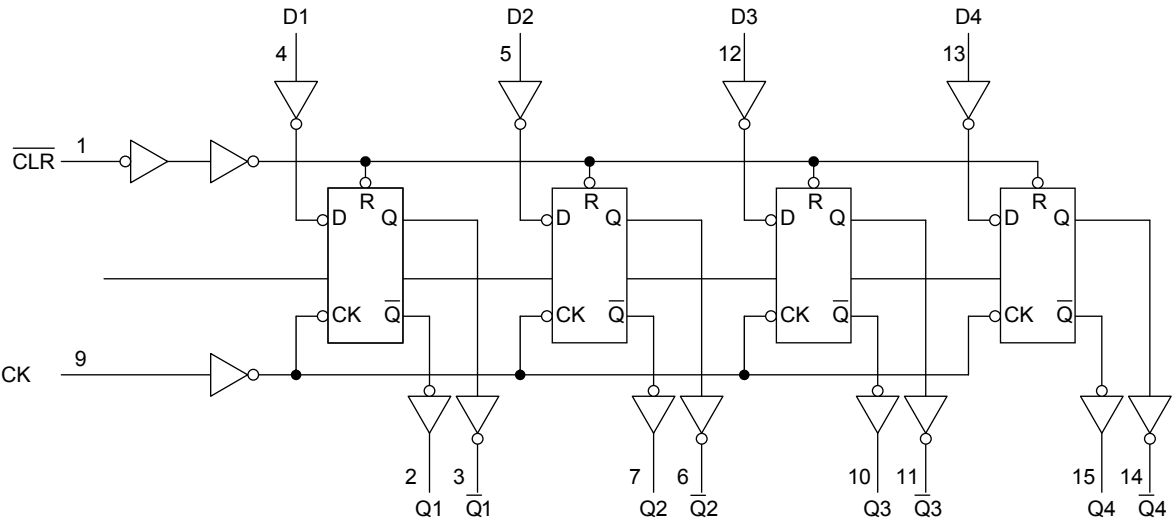


Truth Table

Inputs			Outputs		Function
$\overline{\text{CLR}}$	D	CK	Q	$\overline{\text{Q}}$	
L	X	X	L	H	Clear
H	L		L	H	—
H	H		H	L	—
H	X		Q_n	$\overline{\text{Q}}_n$	No change

X: Don't care

System Diagram



Absolute Maximum Ratings (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V_{CC}	-0.5~7.0	V
DC input voltage	V_{IN}	-0.5~7.0	V
DC output voltage	V_{OUT}	-0.5~ $V_{CC} + 0.5$	V
Input diode current	I_{IK}	-20	mA
Output diode current	I_{OK}	±20	mA
DC output current	I_{OUT}	±25	mA
DC V_{CC} /ground current	I_{CC}	±50	mA
Power dissipation	P_D	180	mW
Storage temperature	T_{stg}	-65~150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	2.0~5.5	V
Input voltage	V_{IN}	0~5.5	V
Output voltage	V_{OUT}	0~ V_{CC}	V
Operating temperature	T_{opr}	-40~85	°C
Input rise and fall time	dt/dv	0~100 ($V_{CC} = 3.3 \pm 0.3$ V)	ns/V
		0~20 ($V_{CC} = 5 \pm 0.5$ V)	

Note: The operating ranges must be maintained to ensure the normal operation of the device.
Unused inputs must be tied to either V_{CC} or GND.

Electrical Characteristics**DC Characteristics**

Characteristics		Symbol	Test Condition		Ta = 25°C			Ta = -40~85°C		Unit	
					VCC (V)	Min	Typ.	Max	Min		Max
Input voltage	High level	VIH	—	2.0	1.50	—	—	1.50	—	V	
				3.0~5.5	VCC × 0.7	—	—	VCC × 0.7	—		
	Low level	VIL	—	2.0	—	—	0.50	—	0.50		
				3.0~5.5	—	—	VCC × 0.3	—	VCC × 0.3		
Output voltage	High level	VOH	VIN = VIH or VIL	IOH = -50 μA	2.0	1.9	2.0	—	1.9	—	V
					3.0	2.9	3.0	—	2.9	—	
					4.5	4.4	4.5	—	4.4	—	
				IOH = -4 mA	3.0	2.58	—	—	2.48	—	
					IOH = -8 mA	4.5	3.94	—	—	3.80	
	Low level	VOL	VIN = VIH or VIL	IOL = 50 μA	2.0	—	0	0.1	—	0.1	
					3.0	—	0	0.1	—	0.1	
					4.5	—	0	0.1	—	0.1	
				IOL = 4 mA	3.0	—	—	0.36	—	0.44	
					IOL = 8 mA	4.5	—	—	0.36	—	
Input leakage current		IIN	VIN = 5.5 V or GND	0~5.5	—	—	±0.1	—	±1.0	μA	
Quiescent supply current		ICC	VIN = VCC or GND	5.5	—	—	4.0	—	40.0	μA	

Timing Requirements (Input: $t_r = t_f = 3 \text{ ns}$)

Characteristics	Symbol	Test Condition	Ta = 25°C		Ta = -40~85°C		Unit
			V _{CC} (V)	Typ.	Limit	Limit	
Minimum pulse width (CK)	$t_w(L)$ $t_w(H)$	—	3.3 ± 0.3	—	5.0	5.0	ns
			5.0 ± 0.5	—	5.0	5.0	
Minimum pulse width ($\overline{\text{CLR}}$)	$t_w(L)$	—	3.3 ± 0.3	—	5.0	5.0	ns
			5.0 ± 0.5	—	5.0	5.0	
Minimum set-up time	t_s	—	3.3 ± 0.3	—	5.0	5.0	ns
			5.0 ± 0.5	—	4.0	4.0	
Minimum hold time	t_h	—	3.3 ± 0.3	—	1.0	1.0	ns
			5.0 ± 0.5	—	1.0	1.0	
Minimum removal time ($\overline{\text{CLR}}$)	t_{rem}	—	3.3 ± 0.3	—	5.0	5.0	ns
			5.0 ± 0.5	—	5.0	5.0	

AC Characteristics (Input: $t_r = t_f = 3 \text{ ns}$)

Characteristics	Symbol	Test Condition			Ta = 25°C			Ta = -40~85°C		Unit
			V _{CC} (V)	C _L (pF)	Min	Typ.	Max	Min	Max	
Propagation delay time (CK-Q)	t_{pLH} t_{pHL}	—	3.3 ± 0.3	15	—	7.5	11.5	1.0	13.5	ns
				50	—	10.0	15.0	1.0	17.0	
			5.0 ± 0.5	15	—	4.8	7.3	1.0	8.5	
				50	—	6.3	9.3	1.0	10.5	
Propagation delay time ($\overline{\text{CLR}}$ -Q)	t_{pHL}	—	3.3 ± 0.3	15	—	6.3	10.1	1.0	12.0	ns
				50	—	8.8	13.6	1.0	15.5	
			5.0 ± 0.5	15	—	4.3	6.4	1.0	7.5	
				50	—	5.8	8.4	1.0	9.5	
Maximum clock frequency	f_{max}	—	3.3 ± 0.3	15	90	140	—	75	—	MHz
				50	50	75	—	45	—	
			5.0 ± 0.5	15	150	210	—	125	—	
				50	85	115	—	75	—	
Output to output skew	t_{osLH} t_{osHL}	(Note 1)	3.3 ± 0.3	50	—	—	1.5	—	1.5	ns
			5.0 ± 0.5	50	—	—	1.0	—	1.0	
Input capacitance	C _{IN}	—	—	—	—	4	10	—	10	pF
Power dissipation capacitance	C _{PD}	(Note 2)	—	—	—	44	—	—	—	pF

Note 1: Parameter guaranteed by design.

$$t_{\text{osLH}} = |t_{\text{pLHm}} - t_{\text{pLHn}}|, t_{\text{osHL}} = |t_{\text{pHLm}} - t_{\text{pHLn}}|$$

Note 2: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{\text{CC (opr)}} = C_{\text{PD}} \cdot V_{\text{CC}} \cdot f_{\text{IN}} + I_{\text{CC}}/4 \text{ (per bit)}$$

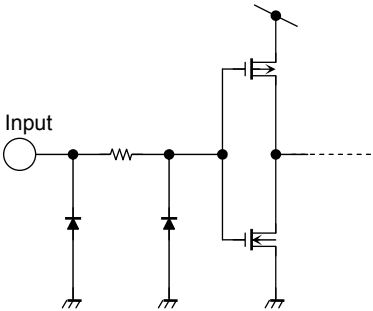
And the total C_{PD} when n pcs of flip-flop operate can be gained by the following equation:

$$C_{\text{PD (total)}} = 30 + 14 \cdot n$$

Noise Characteristics (Input: $t_r = t_f = 3\text{ ns}$)

Characteristics	Symbol	Test Condition	Ta = 25°C			Unit
			V _{CC} (V)	Typ.	Limit	
Quiet output maximum dynamic V _{OL}	V _{OLP}	C _L = 50 pF	5.0	0.4	0.8	V
Quiet output minimum dynamic V _{OL}	V _{OLV}	C _L = 50 pF	5.0	-0.4	-0.8	V
Minimum high level dynamic input voltage V _{IH}	V _{IHD}	C _L = 50 pF	5.0	—	3.5	V
Maximum low level dynamic input voltage V _{IL}	V _{ILD}	C _L = 50 pF	5.0	—	1.5	V

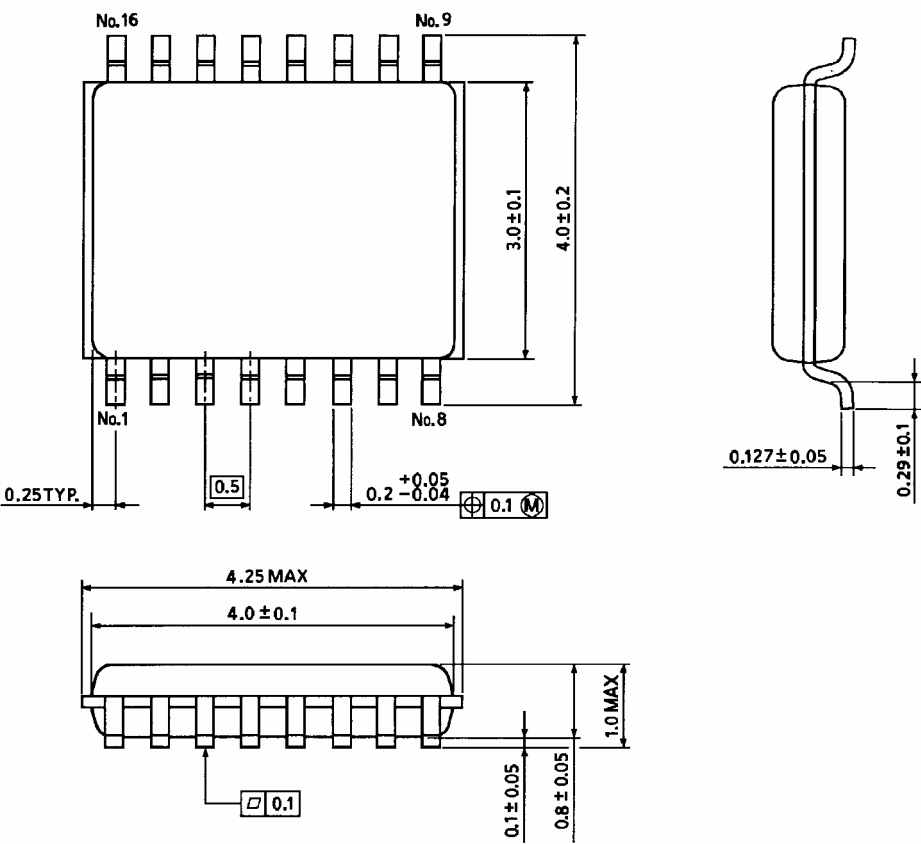
Input Equivalent Circuit



Package Dimensions

VSSOP16-P-0030-0.50

Unit : mm



Weight: 0.02 g (typ.)

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20070701-EN GENERAL

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